

IEC 61058-1
(Third edition – 2000)

**Switches for appliances –
Part 1: General requirements**

CORRIGENDUM 1

Corrections to IEC 61058-1:2000:

Table 15 – Electrical endurance tests for the different types of electronic switches with or without electrical contact(s)

Replace Table 15 by the following new table:

Withdrawing

Table 15 – Electrical endurance tests for the different types of electronic switches with or without electrical contact(s)

Type of electronic switch ³⁾		Test conditions					
		Functional test (7.1.17.1)		Simulated test (7.1.17.2) (Tables 17, 18)		Specific test condition of end application (7.1.17.3)	
		Complete switch	Contacts only	Complete switch	Contacts only	Complete switch	Contacts only
SSD ¹⁾ without electrical contact(s)		TL1 TC5, TC6, TC8 TE1, TE3	---	TL3 TC5, TC6, TC8 TE1, TE3	---	TL4 TC5, TC6, TC8 TE1, TE3	---
SSD with serial contact(s)		TL1 TC5, TC6, TC8 TE1, TE3	Serial contact: TC1, TC4 with TL2 TE1 to TE3 (SSD short-circuited) ²⁾	a) TL1 TC5, TC6, TC8 TE1, TE3 b) TL3 TC5, TC6, TC8 TE1, TE3	a) Serial contact: TL3, TC1, TC4 TE1 to TE3 (SSD short-circuited) ²⁾ b) Serial contact: TL3, TC1, TC7 TE1 to TE3 (SSD short-circuited) ²⁾	TL4 TC5, TC8 TE1, TE3	Serial contact: TC7 with TL4 TE1 to TE3 (SSD short-circuited) ²⁾
SSD with parallel contact(s)		TL1 TC5, TC6, TC8 TE1, TE3	Parallel contact: TC1, TC4 with TL2 TE1 to TE3 (SSD disconnected)	TL3 TC5, TC6, TC8 TE1, TE3	Parallel contact: TL3, TC1, TC4 TE1 to TE3 (SSD disconnected)	TL4 TC5, TC8 TE1, TE3	Parallel contact: TC7 with TL4 TE1 to TE3 (SSD disconnected)
SSD with serial and parallel contact(s)		TL1 TC5, TC6, TC8 TE1, TE3	Serial contact: TC1, TC4 with TL2 TE1 to TE3 (SSD short-circuited) ²⁾ Parallel contact: TC1, TC4 with TL2 TE1 to TE3 (SSD disconnected)	a) TL1 TC5, TC6, TC8 TE1, TE3 b) TL3 TC5, TC6, TC8 TE1, TE3	a) Serial contact: TL3, TC1, TC4 TE1 to TE3 (SSD short-circuited) ²⁾ b) Serial contact: TL3, TC1, TC7 TE1 to TE3 (SSD short-circuited) ²⁾ a) and b) Parallel contact: TL3, TC1, TC7 TE1 to TE3 (SSD disconnected)	TL4 TC5, TC8 TE1, TE3	Serial contact: TC7 with TL4 TE1 to TE3 (SSD short-circuited) ²⁾ Parallel contact: TC7 with TL4 TE1 to TE3 (SSD disconnected)

Table 15 (continued)

TL = type of test load: TL1 = thermal current or maximum rated resistive current, if no thermal current is declared TL2 = maximum rated resistive current TL3 = rated load (7.1.2) TL4 = declared specific load (7.1.2.5) TC = type of test condition: TC1 = increased-voltage test at accelerated speed (17.2.4.1) TC2 = test at slow speed (17.2.4.2) TC3 = test at high speed (17.2.4.3) TC4 = test at accelerated speed (17.2.4.4) TC5 = manual functional test: 20 times at maximum manual operating speed to perform the full function of the electronic switch (17.2.4.5) TC6 = test at minimum load (17.2.4.6) TC7 = test condition according to TC4, number of operating cycles: 1 000 or the declared number of cycles whichever is the lowest (17.2.4.7) TC8 = full number of operating cycles at accelerated speed (17.2.4.8) TE = type of evaluation test: TE1 = functional compliance (17.2.5.1) TE2 = thermal compliance (17.2.5.2) TE3 = insulating compliance (17.2.5.3)	1) SSD = semiconductor switching device. 2) The short circuit shall be performed in a way to allow the terminals and contacts and other parts designed for the maximum rated current to be loaded with the maximum rated current. 3) For combinations of SSD and mechanical contacts, where the function of the SSD and the mechanical contacts are independent of each other, the requirements of this part of IEC 61058 apply for the mechanical contacts. a/b) Testing shall be completed using either method "a" or method "b". The same method shall be used for both complete switch and the contacts only testing. Testing with series and parallel contacts, the parallel contact test is added to either method "a" or "b". Testing to both method "a" and method "b" is not required.
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